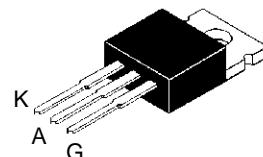


**SCR**
**FEATURES**

- $I_{T(RMS)} = 25A$
- $V_{DRM} = 200V$  to  $800V$
- High surge current capability


**TO220  
non-insulated  
(Plastic)**
**DESCRIPTION**

The S25xxxH series of SCRs uses a high performance MESA GLASS PNPN technology. These parts are intended for general purpose applications.

**ABSOLUTE RATINGS** (limiting values)

Symbol	Parameter	Value	Unit
$I_{T(RMS)}$	RMS on-state current (180° conduction angle)	25	A
$I_{T(AV)}$	Average on-state current (180° conduction angle)	16	A
$I_{TSM}$	Non repetitive surge peak on-state current ( $T_j$ initial = 25°C )	tp = 8.3 ms	270
		tp = 10 ms	250
$I^2t$	$I^2t$ Value for fusing	310	$A^2s$
$dI/dt$	Critical rate of rise of on-state current $I_G = 100\text{ mA}$ $dI_G/dt = 1\text{ A}/\mu\text{s}$ .	100	$A/\mu\text{s}$
$T_{stg}$ $T_j$	Storage and operating junction temperature range	- 40, + 150 - 40, + 125	°C
TI	Maximum lead temperature for soldering during 10s at 4.5mm from case	260	°C

Symbol	Parameter	Voltage				Unit
		B	D	M	N	
$V_{DRM}$ $V_{RRM}$	Repetitive peak off-state voltage $T_j = 125^\circ C$	200	400	600	800	V

## S25xxxH

### THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R <sub>th(j-a)</sub>	Junction to ambient	60	°C/W
R <sub>th(j-c)</sub>	Junction to case for DC	1.6	°C/W

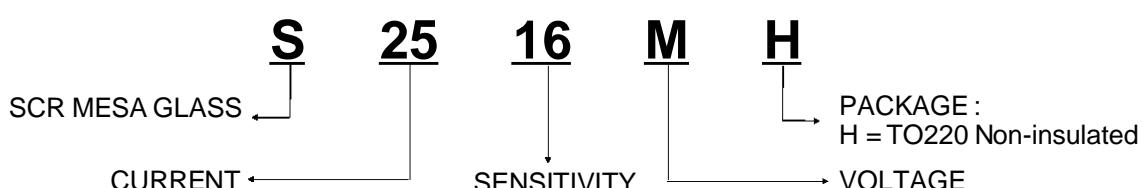
### GATE CHARACTERISTICS (maximum values)

P<sub>G(AV)</sub> = 1 W P<sub>GM</sub> = 10 W (tp = 20 μs) I<sub>GM</sub> = 4A (tp = 20 μs)

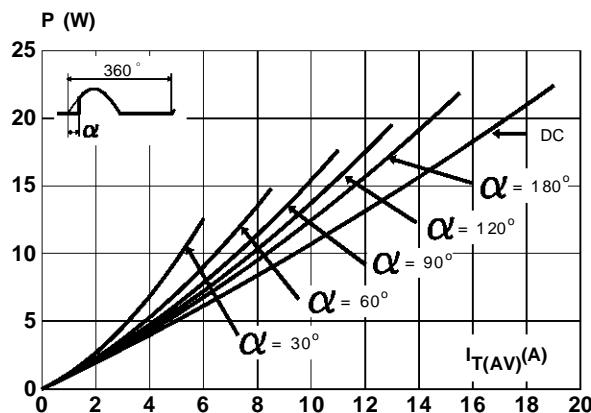
### ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions	Sensitivity		Unit
		14	16	
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =33Ω	T <sub>j</sub> = 25°C	MIN	30
			MAX	75
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =33Ω	T <sub>j</sub> = 25°C	MAX	1.5
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> R <sub>L</sub> =3.3kΩ	T <sub>j</sub> = 125°C	MIN	0.2
t <sub>gt</sub>	V <sub>D</sub> =V <sub>DRM</sub> I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> dI <sub>G</sub> /dt = 1.5A/μs I <sub>G</sub> = 200mA	T <sub>j</sub> = 25°C	TYP	2
I <sub>H</sub>	I <sub>T</sub> = 500mA Gate open	T <sub>j</sub> = 25°C	MAX	115
I <sub>L</sub>	I <sub>G</sub> =1.2 I <sub>GT</sub>	T <sub>j</sub> = 25°C	MAX	230
V <sub>TM</sub>	I <sub>TM</sub> = 50A tp= 380μs	T <sub>j</sub> = 25°C	MAX	1.6
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>D</sub> = V <sub>DRM</sub> V <sub>R</sub> = V <sub>RRM</sub>	T <sub>j</sub> = 25°C	MAX	10
		T <sub>j</sub> = 110°C	MAX	2.5
dV/dt	V <sub>D</sub> =67%V <sub>DRM</sub> Gate open	T <sub>j</sub> = 110°C	MIN	750
t <sub>q</sub>	I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> V <sub>R</sub> =35V dI/dt=25A/μs tp=100μs dV/dt=25V/μs V <sub>D</sub> = 67%V <sub>DRM</sub>	T <sub>j</sub> = 110°C	MAX	100
				μs

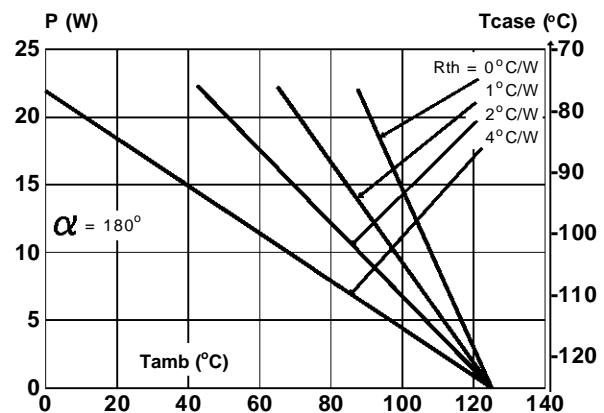
### ORDERING INFORMATION



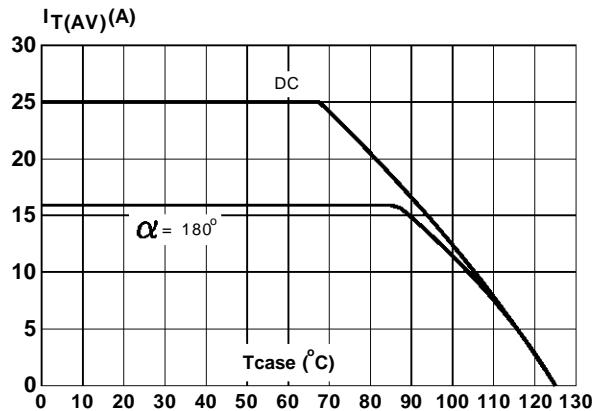
**Fig.1 :** Maximum average power dissipation versus average on-state current.



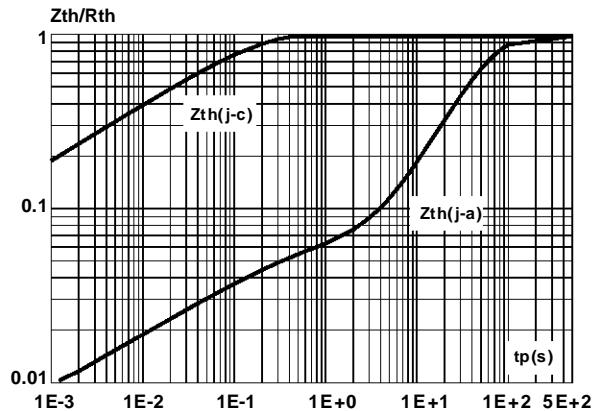
**Fig.2 :** Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tcase) for different thermal resistances heatsink + contact.



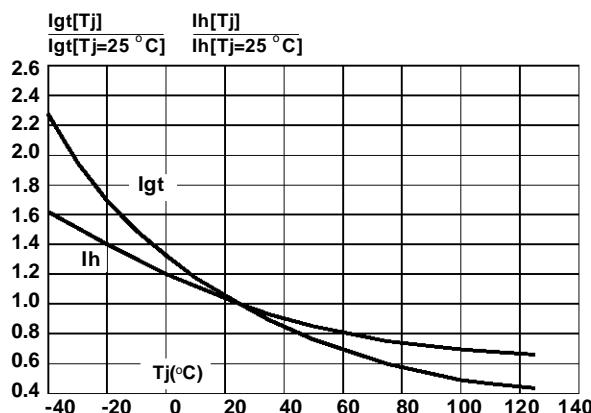
**Fig.3 :** Average on-state current versus case temperature.



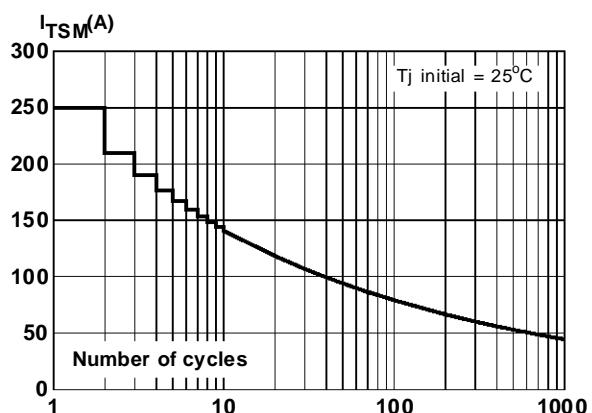
**Fig.4 :** Relative variation of thermal impedance versus pulse duration.



**Fig.5 :** Relative variation of gate trigger current and holding current versus junction temperature.

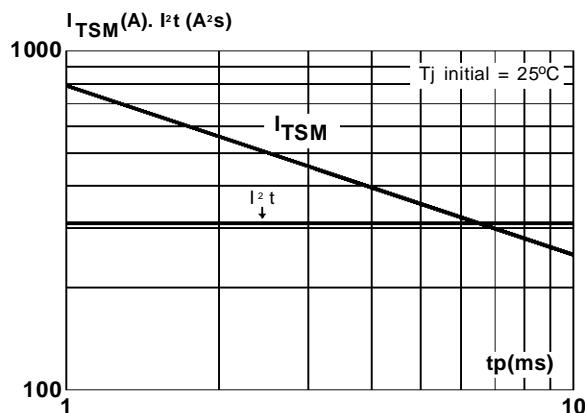


**Fig.6 :** Non repetitive surge peak on-state current versus number of cycles.

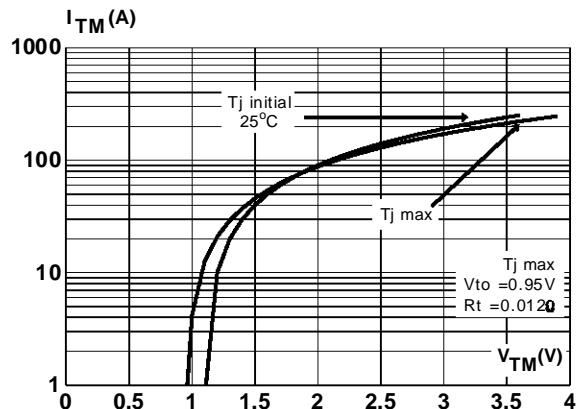


## S25xxxH

**Fig.7 :** Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $t_p \leq 10\text{ms}$ , and corresponding value of  $I^2t$ .



**Fig.8 :** On-state characteristics (maximum values).



**PACKAGE MECHANICAL DATA**  
TO220 Non-insulated (Plastic)

REF.	DIMENSIONS					
	Millimeters			Inches		
	Typ.	Min.	Max.	Typ.	Min.	Max.
A			10.3			0.406
B		6.3	6.5	0.248	0.256	
C			9.1			0.358
D		12.7			0.500	
F			4.2			0.165
G			3.0			0.118
H		4.5	4.7		0.177	0.185
I		3.53	3.66		0.139	0.144
J		1.2	1.3		0.047	0.051
L			0.9			0.035
M	2.7			0.106		
N			5.3			0.209
N1	2.54			0.100		
O		1.2	1.4		0.047	0.055
P			1.15			0.045

Marking : type number

Weight : 1.8 g

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